

CE EMC TEST REPORT

Report No.: DDT-R21032623-1E1

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| Applicant | : | TPV Electronics (Fujian) Co., Ltd. |
| Address | : | Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province |
| Equipment under Test | : | LCD Monitor |
| Model No. | : | **27G2*****("*" = 0-9, A-Z, a-z, +, -, / or blank. All models difference are in sale marketing) |

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Test Report Declare

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| Applicant | : | TPV Electronics (Fujian) Co.,Ltd. |
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| Equipment Under Test | : | LCD Monitor |
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Test Standard Used:

EN 55032:2015, CISPR 32:2015, EN 55032:2015+AC:2016, CISPR 32:2015+cor1:2016, EN 55032:2015+A11:2020, EN 55035:2017, CISPR 35:2016, EN 55035:2017+A11:2020, AS/NZS CISPR 32:2015, AS/NZS CISPR 32:2015 AMD 1:2020, EN 61000-3-2:2014, IEC 61000-3-2:2014, EN IEC 61000-3-2:2019, IEC 61000-3-2:2018, EN 61000-3-3:2013, IEC 61000-3-3:2013, EN 61000-3-3:2013+A1:2019, IEC 61000-3-3:2013+A1:2017

Test Procedure Used:

IEC-61000-4-2:2008, IEC 61000-4-3:2006+A1:2007+A2:2010, IEC-61000-4-4:2012, IEC-61000-4-5:2014
IEC-61000-4-6:2013, IEC-61000-4-8:2009, IEC-61000-4-11:2004, IEC-61000-4-11:2004+A1:2017

We Declare:

The equipment described above is tested and assessed by Tianjin Dongdian Testing Service Co., Ltd. and in the configuration assessed the equipment complied with the standards specified above. The tested and assessed results are contained in this test report and Tianjin Dongdian Testing Service Co., Ltd. is assumed of full responsibility for the accuracy and completeness of these assessments.

After test and evaluation, our opinion is that the equipment in accordance with above standards.

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| Date of Receipt: | Apr. 07, 2021 | Date of Test: | Apr. 07, 2021 - Apr. 16, 2021 |



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Approved By:

Aaron Zhang

Aaron Zhang/EMC Manager

Note: This report applies to above tested sample only. This report shall not be reproduced in parts without written approval of Tianjin Dongdian Testing Service Co., Ltd.

Revision History

| Rev. | Revisions | Issue Date | Revised By |
|------|---------------|---------------|------------|
| --- | Initial issue | Apr. 18, 2021 | |
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